

LIST OF REFERENCES CITED BY APPLICANT

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DOCKET NO.: 5408/1H638US1 SERIAL NO: 10/087,206
 APPLICANT: Patrick J. LUTZ et al. FILING DATE: February 28, 2002
 CONFIRMATION NO:

U.S. PATENT DOCUMENTS

<u>*EXAMINER INITIALS</u>	<u>DOCUMENT NUMBER</u>	<u>DATE</u>	<u>NAME</u>	<u>CLASS</u>	<u>SUBCLASS</u>	<u>FILING DATE</u>
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<u>*EXAMINER INITIALS</u>	<u>DOCUMENT NUMBER</u>	<u>DATE</u>	<u>COUNTRY</u>			<u>TRANSLATION</u>
				<u>CLASS</u>	<u>SUBCLASS</u>	<u>YES</u>
<i>John Szw</i>	1. JP 4049207	2/18/1992	JP	A01N	25/04	Abstract only
	2. JP 6313269	5/25/1999	JP	A01N	47/10	Abstract only

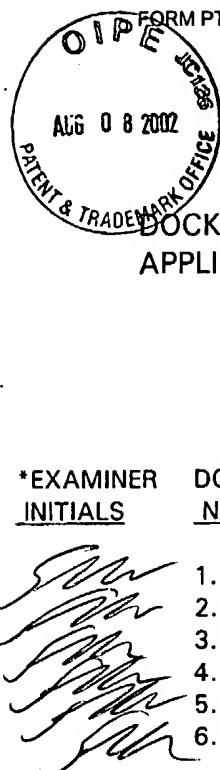
OTHER REFERENCES
(INCLUDING AUTHOR, TITLE DATE, PERTINENT PAGES, ETC.)

*EXAMINER INITIALS

John 3. International Search Report

EXAMINER: *L. Mark Otag*DATE CONSIDERED: 9/21/2004

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<i>JMM</i>	1. 3,097,131	7/9/63	Ueno et al.	167	31	4/1/60
<i>JMM</i>	2. 4,844,891	7/4/89	Rosen et al.	424	76	2/3/88
<i>JMM</i>	3. 5,073,570	12/17/91	Tseng	514	533	2/16/89
<i>JMM</i>	4. 5,670,160	9/23/97	Eggensperger et al.	424	405	1/30/96
<i>JMM</i>	5. 5,885,593	3/23/99	Epstein	424	401	7/17/96
<i>JMM</i>	6. 5,906,981	5/25/99	Gagliani	A61K	31/715	6/4/96

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<i>JMM</i>	7. 57058625	04/08/82	JP	A61K	31/19	Abstract only	
<i>JMM</i>	8. 57057624	04/08/82	JP	A61K	31/19	X (Abstract)	
<i>JMM</i>	9. 5350245	05/08/78	JP	C08/K	5/09	X (Abstract)	

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<i>[Signature]</i>	1. 6-313269	11/8/94	JP	D06M	13/425	X	
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OTHER REFERENCES
(INCLUDING AUTHOR, TITLE DATE, PERTINENT PAGES, ETC.)

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